

Applicat	ion/Control No.	Applicant(s)/Patent und Reexamination	ler
10/690,0	686	AKKIRAJU ET AL.	
Examine	or	Art Unit	
John M.	Winter	3621	

	SEARCHED				
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Class	Subclass	Date	Examiner		
705	50	6/24/2007	JMW		

INTERFERENCE SEARCHED					
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SEA (INCLUDING	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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